

**Search Notes****Application/Control No.**

10/779,336

**Examiner**

MARK MAIS

**Applicant(s)/Patent under Reexamination**

HIGUCHI ET AL.

**Art Unit**

2419

**SEARCHED**

Class	Subclass	Date	Examiner
370	254-256 310 312		
	313 328 329		
	335 336 338		
	342 345 347		
	352 386 388		
	389 390 392		
	395.1		
	395.21		
	396 400 408		
	422 429		
	464 467	8/28/2009	MAM

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See Inventorship Search/See Attached Electronic Search	12/11/2007	MAM
See Attached Electronic Search [updated]	8/11/2008	MAM
See Attached Electronic Search [updated]	1/20/2009	MAM
See Attached Electronic Search [updated]	8/28/2009	MAM

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner